

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re: Chung et al.

Serial No.: To Be Assigned

Filed: Concurrently Herewith

For: **METHOD FOR MANUFACTURING SEMICONDUCTOR DEVICES AND  
INTEGRATED CIRCUIT CAPACITORS WHEREBY DEGRADATION OF  
SURFACE MORPHOLOGY OF A METAL LAYER FROM THERMAL  
OXIDATION IS SUPPRESSED**

October 22, 2003

Mail Stop PATENT APPLICATION  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

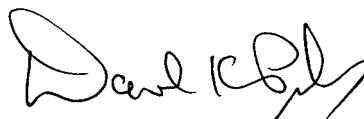
**INFORMATION DISCLOSURE STATEMENT**

Sir:

Attached is a list of documents on form PTO-1449 and on two PTO-892s. Since the benefit of this application is claimed under 35 U.S.C. §120, no copies need to be furnished in accordance with 37 C.F.R. §1.98(d); however, copies will be furnished on request. It is requested that these documents be considered by the Examiner and officially made of record in accordance with the provisions of 37 C.F.R. §1.56 and Section 609 of the MPEP.

No fee is believed due. However, the Commissioner is hereby authorized to charge any deficiency or credit any overpayment to Deposit Account No. 50-0220.

Respectfully submitted,



David K. Purks

Registration No. 44,635

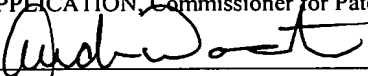
Correspondence Address:  
Myers Bigel Sibley & Sajovec, P.A.  
P. O. Box 37428  
Raleigh, North Carolina 27627  
Telephone: (919) 854-1400  
Facsimile: (919) 854-1401  
Customer No. 20792

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I hereby certify that this correspondence is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" service under 37 CFR § 1.10 on the date indicated above and is addressed to: Mail Stop PATENT APPLICATION, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

  
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Audra Wooten



# **Notice of References Cited**

Application/Control No.

10/101,353

Applicant(s)/Patent Under  
Reexamination  
CHUNG ET AL.

Examiner

David L. Hogans

Art Unit

2813

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## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,395,053	05-2002	Fau et al.	75/362
	B	US-5,780,115	07-1998	Park et al.	427/539
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,399,459	06-2002	Al-Shareef et al.	438/240
	B	US-6,184,073	02-2001	Lage et al.	438/238
	C	US-6,204,203	03-2001	Narwankar et al.	438/785
	D	US-5,972,722	10-1999	Visokay et al.	438/240
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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